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 INFORMATION
 See Also Sheet 1

CONFIRMATION NO. 8779

SERIAL NUMBER	FILING DATE	CLASS	GROUP ART UNIT	ATTORNEY DOCKET NO.
08/891,511	08/27/2001 RULE	438	2812	010819

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CONTINUING DATA

FOREIGN APPLICATIONS

JAPAN 2000-183104 08/27/2000
 JAPAN 2000-229101 07/28/2000
 JAPAN 2000-335834 11/02/2000
 JAPAN 2001-11218 01/18/2001
 JAPAN 2001-31901 02/08/2001
 JAPAN 2001-31868 02/08/2001
 JAPAN 2001-33588 02/09/2001
 JAPAN 2001-35088 02/13/2001
 JAPAN 2001-158862 05/28/2001
 JAPAN 2001-182041 05/30/2001
 JAPAN 2001-189304 08/22/2001

 IF REQUIRED, FOREIGN FILING LICENSE GRANTED
 08/28/2001

Foreign Priority claimed	<input checked="" type="checkbox"/> Yes <input type="checkbox"/> No	STATE OR COUNTRY JAPAN	SHEETS DRAWING 30	TOTAL CLAIMS 60	INDEPENDENT CLAIMS 13
35 USC 119 (b)-(d) conditions met	<input checked="" type="checkbox"/> Yes <input type="checkbox"/> No <input type="checkbox"/> Not clear				
Filed and acknowledged	<i>Mark Brown</i> Attorney for Applicant				
ADDRESS	21839				
TITLE	Inspection system by charged particle beam and method of manufacturing devices using the system				

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